

30V N-Channel Enhancement Mode MOSFET

Description

The AP250N03NF uses advanced **APM-SGT V** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 30V$ $I_D = 250A$

$R_{DS(ON)} < 0.7m\Omega$ @ $V_{GS}=10V$ (**Type: 0.55mΩ**)

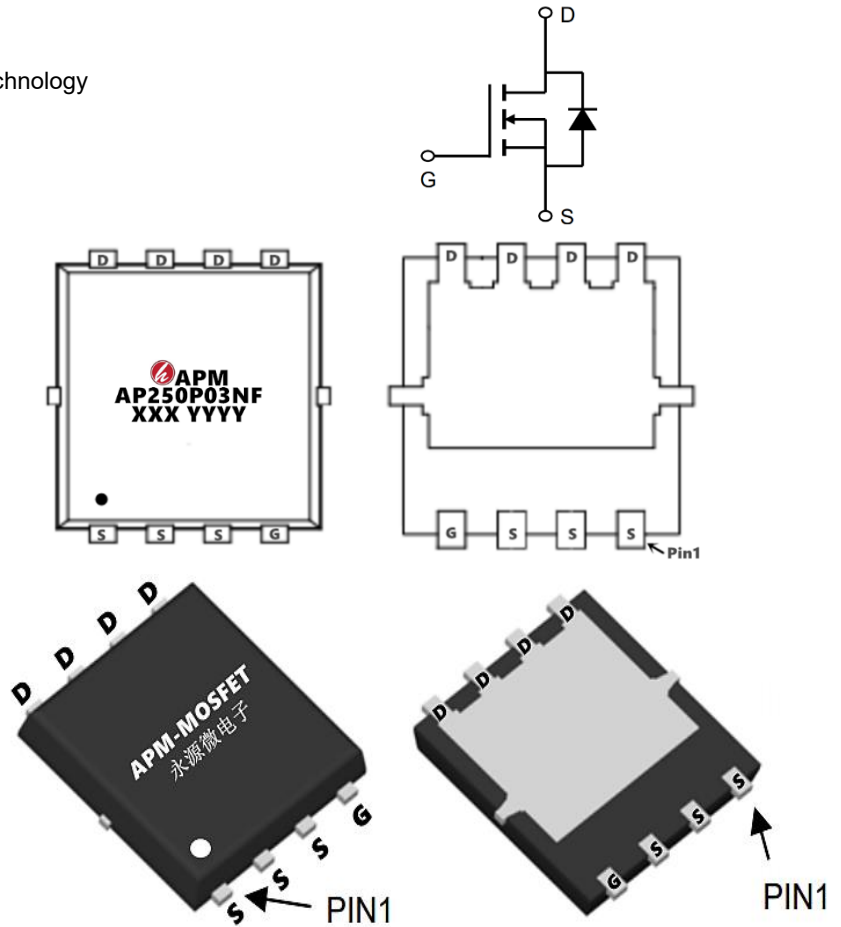
Application

Boost driver

Brushless motor

BLDC

Clip packaging process



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP250N03NF	PDFN5*6-8L	AP250N03NF XXX YYYY	5000

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_{D@TC=25^\circ C}$	Continuous Drain Current, $V_{GS} @ 10V$	250	A
$I_{D@TC=100^\circ C}$	Continuous Drain Current, $V_{GS} @ 10V$	220	A
I_{DM}	Pulsed Drain Current ²	1500	A
E_{AS}	Single Pulse Avalanche Energy ³	1332	mJ
I_{AS}	Avalanche Current	73	A
$P_{D@TC=25^\circ C}$	Total Power Dissipation ⁴	165	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient 1	25	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	0.75	$^\circ C/W$

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	30	36	---	V
VGS(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.2	1.6	2.5	V
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =10V, I _D =20A	---	0.55	0.7	mΩ
		V _{GS} =4.5V, I _D =10A	---	0.7	1.0	mΩ
IDSS	Drain-Source Leakage Current	V _{DS} =30V, V _{GS} =0V, T _J =25°C	---	---	1	uA
IDSS	Drain-Source Leakage Current	V _{DS} =30V, V _{GS} =0V, T _J =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA
gfs	Forward Transconductance	V _{DS} =10V, I _D =20A	---	130	---	S
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	---	1.4	---	Ω
Ciss	Input Capacitance	V _{DS} =15V, V _{GS} =0V, f=1MHz	---	9130	---	pF
Coss	Output Capacitance		---	3360	---	
Crss	Reverse Transfer Capacitance		---	300	---	
Q _g	Total Gate Charge (4.5V)	V _{DS} =15V, V _{GS} =10V, I _D =20A	---	147.4	---	nC
Q _{gs}	Gate-Source Charge		---	25.2	---	
Q _{gd}	Gate-Drain Charge		---	18	---	
Td(on)	Turn-On Delay Time	V _{DD} =15V, V _{GS} =10V, R _G =3Ω, I _D =20A	---	14.8	---	ns
T _r	Rise Time		---	15.6	---	
Td(off)	Turn-Off Delay Time		---	106	---	
T _f	Fall Time		---	49	---	
IS	Continuous Source Current ^{1,5}	V _G =V _D =0V, Force Current	---	---	250	A
VSD	Diode Forward Voltage ²	V _{GS} =0V, I _S =20A, T _J =25°C	---	---	1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 20Z copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、The EAS data shows Max. rating . The test condition is VDD=40V,VGS =10V,L=0.5mH,IAS =73A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

Typical Characteristics

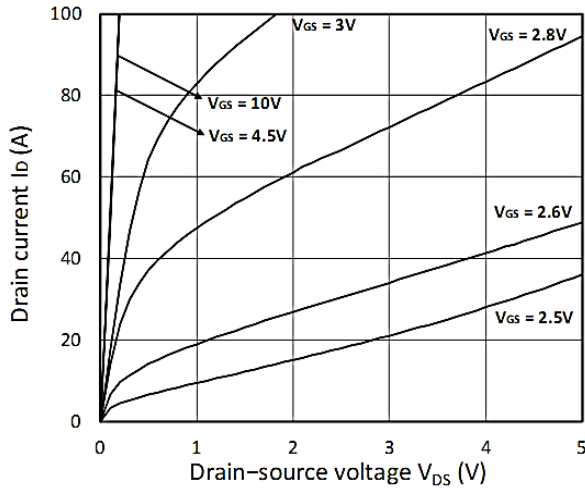


Figure 1. Output Characteristics

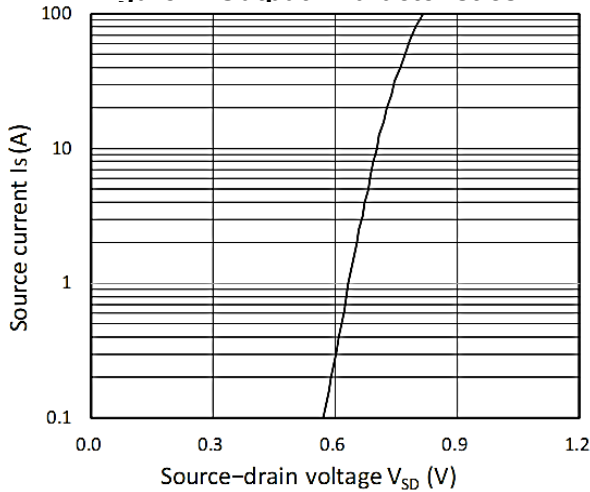


Figure 3. Forward Characteristics of Reverse

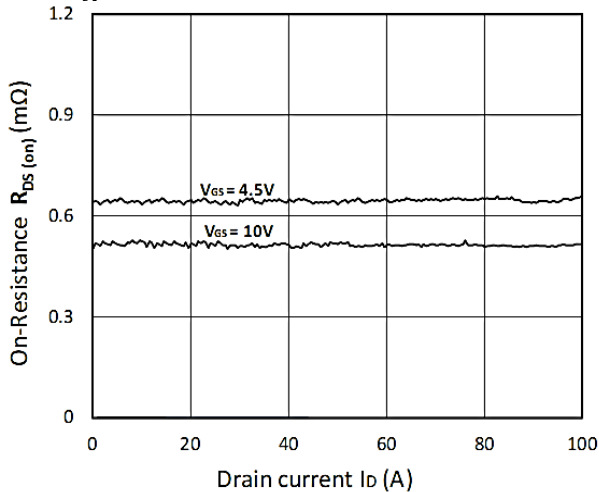


Figure 5. R_DS(ON) vs. I_D

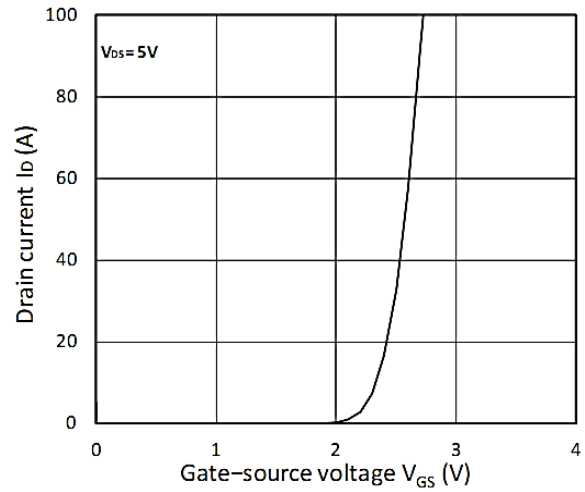


Figure 2. Transfer Characteristics

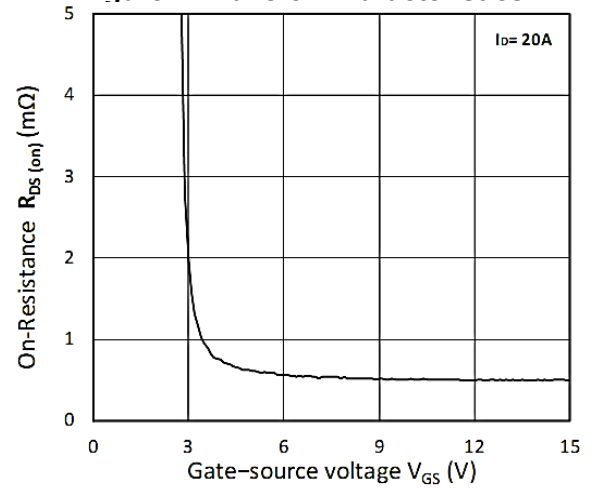


Figure 4. R_DS(ON) vs. V_GS

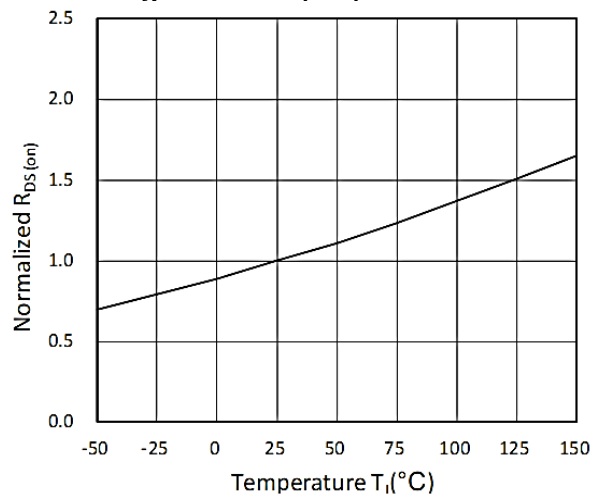


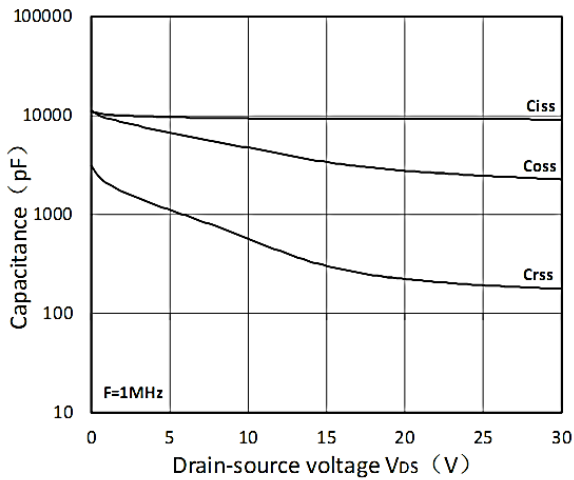
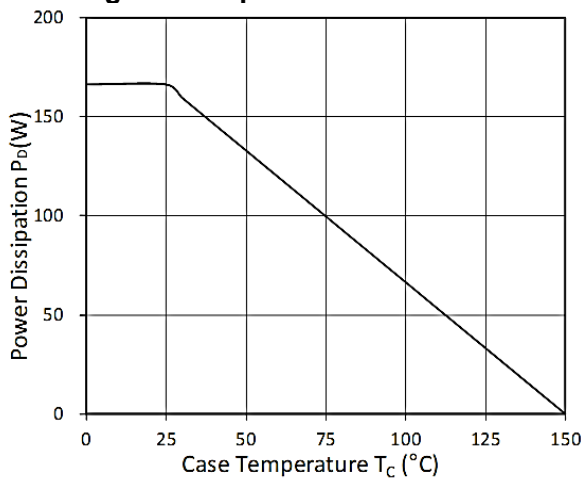
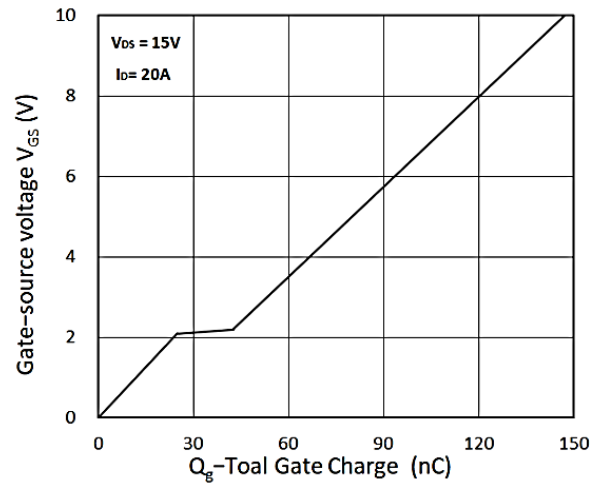
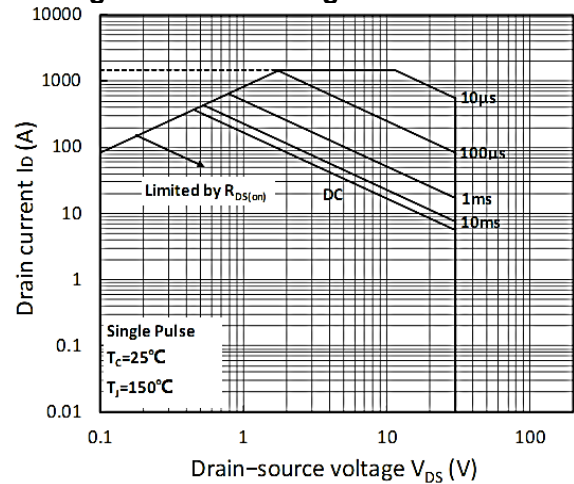
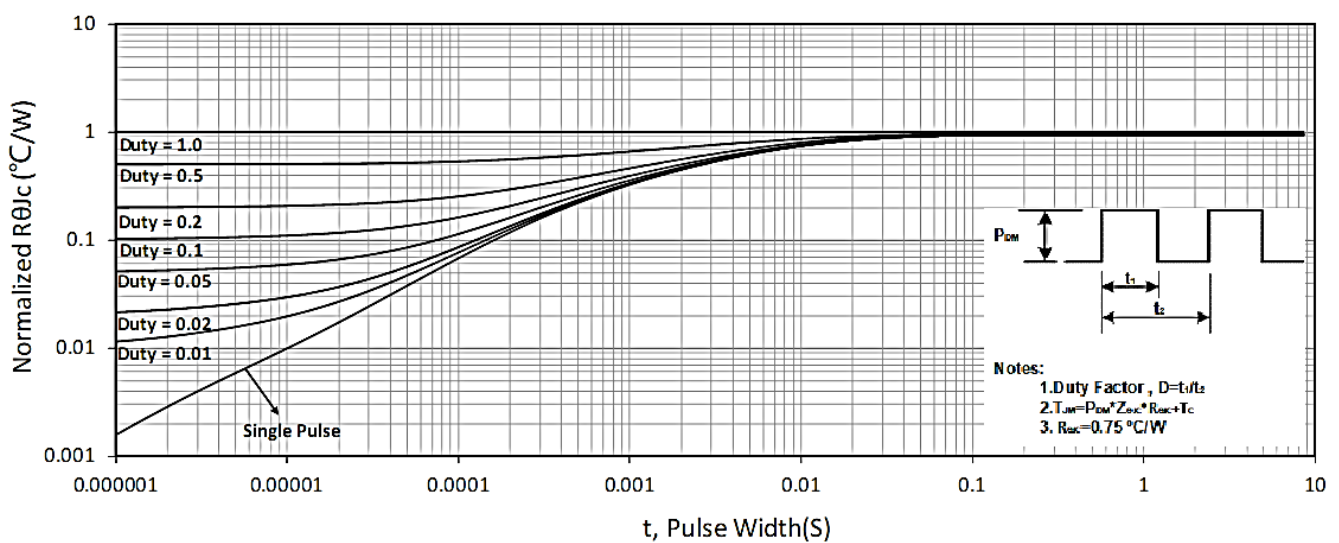
Figure 6. Normalized R_DS(on) vs. Temperature

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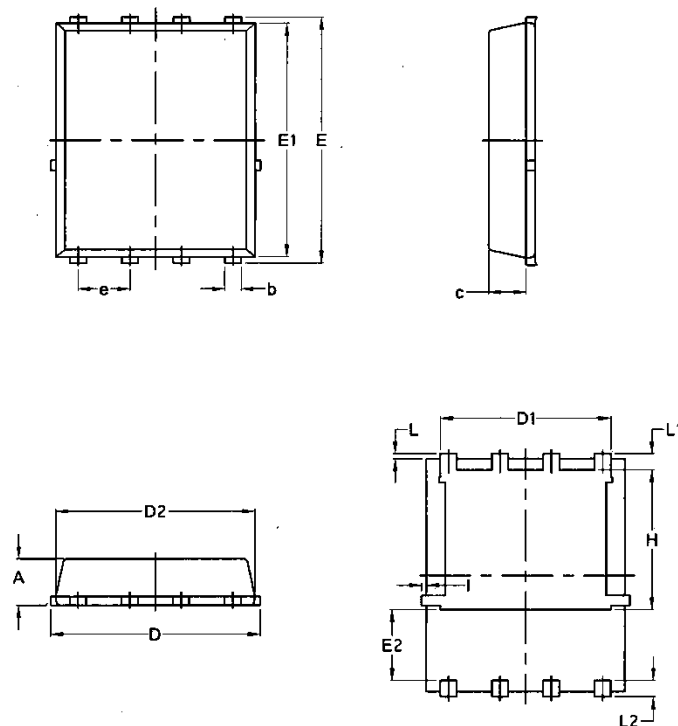
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**Figure 7. Capacitance Characteristics****Figure 9. Power Dissipation****Figure 8. Gate Charge Characteristics****Figure10. Safe Operating Area****Figure 11. Normalized Maximum Transient Thermal Impedance**

Package Mechanical Data-PDFN5*6-8L-JQ Single



Symbol	Common			
	mm		Inch	
	Mim	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070

30V N-Channel Enhancement Mode MOSFET**Attention**

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Edition	Date	Change
RVE1.0	2023/9/23	Initial release

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